Characterization of the nonlinear optical susceptibilities of monolayer MoS₂ and comparison with graphene

C. F. Phelan^{1*}

R.I. Woodward², R.T. Murray², R.E.P. de Oliveira¹, T.H. Runcorn², E.J.R. Kelleher², S. Li³, E.C. de Oliveira¹, G.J.M. Fechine¹, G. Eda³, C.J.S. de Matos¹

¹ MackGraphe–Graphene and Nanomaterials Research Center, Mackenzie Presbyterian University, São Paulo, Brazil

 ² Femtosecond Optics Group, Department of Physics, Imperial College London, London, UK
³ Centre for Advanced 2D Materials, National University of Singapore, Singapore

*ciphelan@tcd.ie

Abstract

We report the determination of the second and, for the first time, third order optical nonlinear susceptibilities of monolayer MoS₂ by measurements of second and third harmonic generation [1]. The measurements were made using a nonlinear optical microscope (Figure 1) with a 1560nm wavelength (non-resonant) pump beam. The experimental system also enables high resolution third harmonic imaging. The measured susceptibilities, inferred from the dependence of third harmonic intensity on pump beam intensity and interpreted as sheet susceptibilities [2] are:

$$\begin{aligned} \left| \chi_s^{(2)} \right| &= 2 \times 10^{-20} m^2 V^{-1} \text{ and} \\ \left| \chi_s^{(3)} \right| &= 1.7 \times 10^{-28} m^3 V^{-2} \end{aligned}$$

The third order susceptibility of graphene was determined, using the same experimental setup, to be approximately 3.4 times lower than that of MoS₂ (Figure 2). The results highlight the potential of MoS₂ for low footprint nonlinear optical devices in the telecommunications C-band.

References

- [1] R. I. Woodward et al, 2D mater, **4** (2016) 011006
- [2] Y. R. Shen, An. Rev. Chem, **40** (1989) 327



Figure 1: The nonlinear optical microscope used for the measurements.



Figure 2: Dependence of third harmonic intensities on pump beam intensity in monolayer MoS₂ and graphene.

Acknowledgements

This work is funded by the São Paulo Research Foundation (FAPESP), grants 2012/50259-8, 2014/50460-0 and 2015/11779-4, and the Imperial College London Global Engagement Programme. This work is also partially funded by CNPq and Fundo Mackenzie de Pesquisa. GE acknowledges Singapore National Research Foundation for funding under NRF Research Fellowship (NRF-NRFF2011-02) and Medium-Sized Centre Programme. CP, EJRK and RIW are supported by fellowships from FAPESP (grant 2015/12734-4), Royal Academy of Engineering and EPSRC, respectively.